

APPROVAL SHEET

Qi Hardware Inc

Item: 49US(SMD) Crystal

Spec. no: R49SSA-028636-F20-YYY-YQA

Freq: 28.63636 MHz

| Customer Approved | Checked By | Issued By |
|--------------------------|------------|-----------|
| | 陳慧美 | 魏美純 |

友桂電子股份有限公司 YOKETAN CORPORATION

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REVISION HISTORY

| N/A | INITIAL ISSUE | 2010/12/20 | N/A | Miffy Wai |
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SPECIFICATION OF CRYSTAL UNITS

YOKETAN CORP.

Customer: Qi SPEC NO: R49SSA-028636-F20-YYY-YQA

Date: 20-Dec-10

1 General

1-1 Enclosure: HC-49SMD (Lead Free Parts)

1-2 Application:

1-3 Overtone Order: Fundamental

1-4 Crystal unit Frequency: 28.63636 MHz

1-5 Frequency Deviation:

1-5-1 At Reference Temperature : \pm 30ppm at 25 \pm 3 1-5-2 At Operating Temperature : \pm 30ppm in 1-6

1-6 Operating Temperature Range : -10 to +60

1-7 Storage Temperature Range : -40 to +85

2 Circuit

2-1 Circuit : 250B

2-2 Load Capacitance : 20pF±0.3pF

2-3 Level of Drive: 100uW

3 Electrical Performance

3-1 Equivalent Series Resistance: Less than 50 ohms

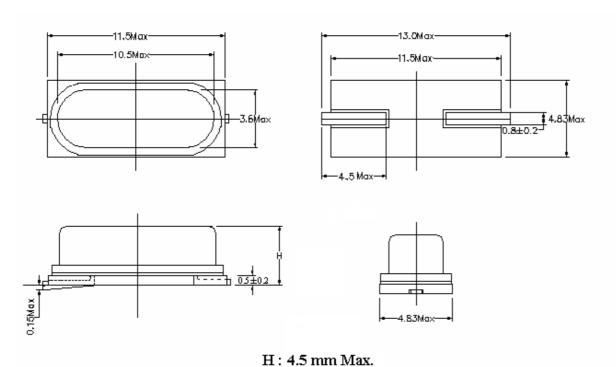
3-2 Electrostatic Capacitance : 5.0pF Max.

3-3 Insulation Resistance: More than 500Mohms at DC100V

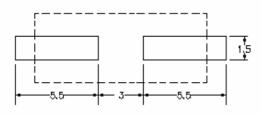
3-4 Aging: \pm 5ppm/year Max

4 Marking 28.63636 Y

Dimension

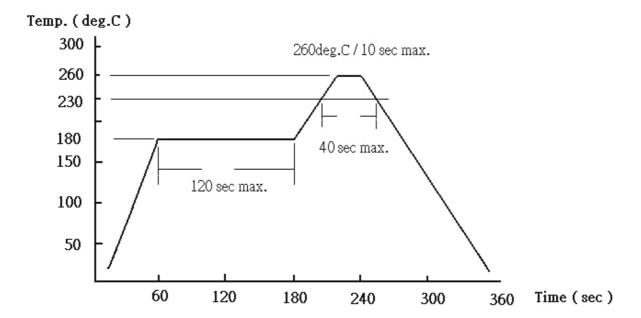


Recommended Soldering Pattern



| | Date | Name | Unit:mm | | |
|----------|------------|------|---------|----------------|-----------------|
| Drawn | 6.Jun.2009 | Leo | Title | | Drawing No. |
| Checked | 6.Jun.2009 | Iris | Dimensi | on of External | PKX-1304845-112 |
| Approved | 6.Jun.2009 | Wan | | | |

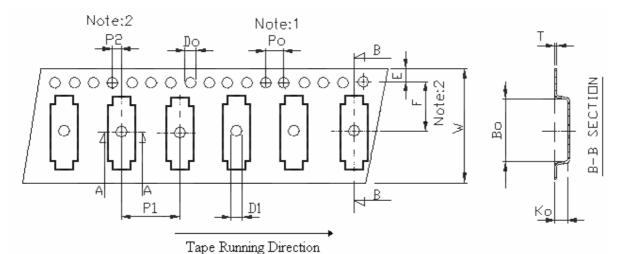
Soldering reflow

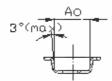


Reliability Test (applicable to 49(50) type .U type and Tuning Fork X'tal)

| | The second second | Specification | | | |
|------------------------------------|--|--|---|--|--|
| Test Items | Test Condition | Dip | SMD | | |
| 1. Gross Leak Test | FC-40 125 /30sec | No continuous bubble | | | |
| 2. Fine Leak Test | Bombing of He 4kg/cm ² for 2 hours | Less than 5*10^-8at | m.c.c./sec, Helium | | |
| 3. Drop Test | a ~19.999MHz(Fund.) 100 cm height b. 20~29.999MHz(Fund.) 50 cm height c. 30~ MHz(Fund.) 20 cm height on hard wooden surface / 3 times (thickness more than 30 mm) | F ± 10PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |
| 4. Vibration Test | Freq. range: 10~55Hz Peak to peak amplitude:1.5mm 3 direction(X,Y,Z), each 60min. | F ± 10PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |
| 5. Resistance to Soldering Test | a. IR Reflow furnace with the condition 2 times. Peak temp.260±3 , 10±1 sec. | NA | F ±10PPM, C.I within spec. For SMD type only. | | |
| | b. Dip terminals in a 245±5 solder station(pool) Dipping depth 0.5mm(Min) Dipping time 5±0.5 sec. | At least 90% by 30X magnification of each dipped area shall be covered by fresh solder. For DIP type only. | NA | | |
| 6. Bending Test | Bending cycle : 1 cycle $0^{\circ} -> 45^{\circ} -> 0^{\circ} -> 45^{\circ} -> 0^{\circ}$ | F ±5PPM, C.I within spec. For DIP type only. | NA | | |
| 7. Shearing Test | Weight : 5N, Test duration : 10±1 sec | NA | F ±10PPM, C.I within spec. For SMD type only. | | |
| 8. Low Temp. Exposure Test | -40±3 , 240±12 hrs | $F \pm 10$ PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |
| 9. Aging Test | 85±3 , 240±12hrs | $F \pm 10$ PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |
| 10. High Temp. & Humidity Test | | $F \pm 10$ PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |
| 11. Temperature Cycling Test | -25±3 /15±3min ~ +85±3 /15±3min 15cycles | F ± 10PPM, C.I within spec. | F ±10PPM, C.I within spec. | | |

Taping





A-A SECTION

| A0= | 5.00± 0.10 | mm |
|-----|------------|----|
| | | |

$$K_0 = 4.25 \pm 0.20$$
 mm

Unit: mm

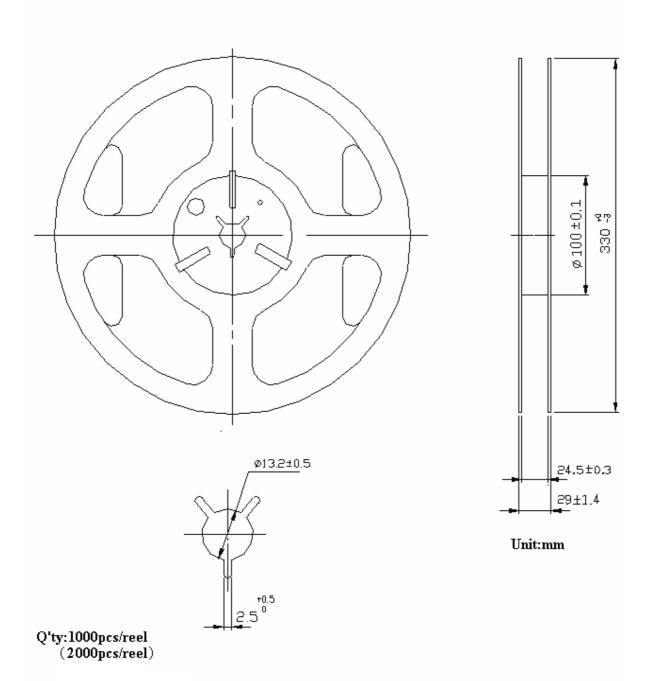
| Symbol | Spec. | | |
|-------------|----------------------------|--|--|
| K1 | _ | | |
| Po | 4,0±0,10 | | |
| P1 | 8.0± 0.10 or 12.0± 0.10 | | |
| P2 | 2.00±0.10 | | |
| Do | 1.50± 0.10 | | |
| D1 | 1.50(MIN) | | |
| E 1.75±0.10 | | | |
| F | 11.50± 0.10 | | |
| 10Po | 40.0±0.20 | | |
| W | 24.0±0.30 | | |
| Т | 0.40±0.05 | | |

Notice:

- 1. 10 Sprocket hole pitch cumulative talerance is $\pm 0.2 \text{mm}$
- 2. Pocket position relative to sprocket hole measured as true position of pocket not pocket hole.
- 3. As & Bo measured on a place 0.3mm above the bottom of the pocket to top surface of the carrier.
- Ko measured from a plane on the inside bottom of the pocket to the top surface of the carrier.
- 5. Carrier camber shall be not than 1mm per 100mm through a length of 250mm.

| | Date | Name | Unit:mm | | |
|----------|-------------|------|---------------|----------|--------------------|
| Drawn | 27.Oct.2008 | Leo | Title | | Drawing No. |
| Checked | 27.Oct.2008 | Iris | Tape & Reel D | imension | C009-051542-X-1003 |
| Approved | 27.Oct.2008 | Wan | | | |

Reel



| | Date | Name | Unit:mm | |
|----------|-------------|------|-----------------------|------------------|
| Drawn | 27.Oct.2008 | Leo | Title | Drawing No. |
| Checked | 27.Oct.2008 | Iris | Tape & Reel Dimension | C009-1324-X-1002 |
| Approved | 27.Oct.2008 | Wan | r | |



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YOKETAN CORPORATION 28-2, NAN 2ND ROAD, T. E. P. Z, TAICHUNG, TAIWAN



The following sample(s) was/were submitted and identified by/on behalf of the client as:

Sample Description **CRYSTAL UNIT**

Style/Item No. 50U(T)(T3), 49U(T)(T3), 49US, 49SMD SERIES/ATXX SERIES

Sample Receiving Date 2009/12/31

Testing Period 2009/12/31 TO 2010/01/08

Test Result(s) Please refer to next page(s).

Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD.

Chemical Laboratory - Taipei

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Test Result(s)

PART NAME NO.1 MIXED ALL PARTS (9 TYPES)

| Test Item (s): | Unit | Method | MDL | Result | |
|--|--|--|-----|--------|--|
| rest item (s). | Offic | Wethod | MDL | No.1 | |
| Cadmium (Cd) | mg/kg | With reference to IEC 62321: 2008 and performed by ICP-AES. | 2 | n.d. | |
| Lead (Pb) | mg/kg | With reference to IEC 62321: 2008 and performed by ICP-AES. | 2 | n.d. | |
| Mercury (Hg) | mg/kg | With reference to IEC 62321: 2008 and performed by ICP-AES. | 2 | n.d. | |
| Hexavalent Chromium Cr(VI) by alkaline extraction | mg/kg | With reference to IEC 62321: 2008 and performed by UV-VIS. | 2 | n.d. | |
| Perfluorooctane sulfonates (PFOS) PFOS – Acid PFOS – Metal Salt PFOS – Amide | mg/kg | With reference to US EPA 3540C: 1996 method for PFOS Content. Analysis was performed by LC/MS. | 10 | n.d. | |
| PFOA (CAS No.: 000335-67-1) | mg/kg | With reference to US EPA 3540C: 1996 method for PFOA Content. Analysis was performed by LC/MS. | 10 | n.d. | |
| Halogen | | | | | |
| Halogen-Fluorine (F) (CAS No.: 014762-94-8) | | | 50 | n.d. | |
| Halogen-Chlorine (CI) (CAS No.: 022537-15-1) | ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,, | With reference to BS EN | 50 | n.d. | |
| Halogen-Bromine (Br) (CAS No.: 010097-32-2) | mg/kg | 14582:2007. Analysis was performed by IC. | 50 | n.d. | |
| Halogen-lodine (I) (CAS No.: 014362-44-8) | | | 50 | n.d. | |

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| Toot Itom (a): | I Imit | Mathad | MDL | Result |
|--------------------------|--------|---|-----|--------|
| Test Item (s): | Unit | Unit Method | | No.1 |
| Sum of PBBs | | | - | n.d. |
| Monobromobiphenyl | | | 5 | n.d. |
| Dibromobiphenyl | | | 5 | n.d. |
| Tribromobiphenyl | | | 5 | n.d. |
| Tetrabromobiphenyl | | | 5 | n.d. |
| Pentabromobiphenyl | | | 5 | n.d. |
| Hexabromobiphenyl | | | 5 | n.d. |
| Heptabromobiphenyl | | | 5 | n.d. |
| Octabromobiphenyl | | | 5 | n.d. |
| Nonabromobiphenyl | | With reference to IEC 62321: 2008 and performed by GC/MS. | 5 | n.d. |
| Decabromobiphenyl | | | 5 | n.d. |
| Sum of PBDEs | mg/kg | | = | n.d. |
| Monobromodiphenyl ether | | | 5 | n.d. |
| Dibromodiphenyl ether | | | 5 | n.d. |
| Tribromodiphenyl ether | | | 5 | n.d. |
| Tetrabromodiphenyl ether | | | 5 | n.d. |
| Pentabromodiphenyl ether | | | 5 | n.d. |
| Hexabromodiphenyl ether | | | 5 | n.d. |
| Heptabromodiphenyl ether | | | 5 | n.d. |
| Octabromodiphenyl ether | | | 5 | n.d. |
| Nonabromodiphenyl ether | | | 5 | n.d. |
| Decabromodiphenyl ether | | | 5 | n.d. |

Note : 1. mg/kg = ppm; 0.1wt% = 1000ppm

- 2. n.d. = Not Detected
- 3. MDL = Method Detection Limit
- 4. " " = Not Regulated
- 5. The sample(s) was/were analyzed on behalf of the applicant as mixing sample in one testing. The above result(s) was/were only given as the informality value.

PFOS Reference Information: Directive 2006/122/EC

- (1) May not be placed on the market or used as a substance or constituent of preparations in a concentration equal to or higher than 0.005 % by mass.
- (2) May not be placed on the market in semi-finished products or articles, or parts thereof, if the concentration of PFOS is equal to or higher than 0.1 % by mass calculated with reference to the mass of structurally or microstructurally distinct parts that contain PFOS or, for textiles or other coated materials, if the amount of PFOS is equal to or higher than 1µg/m2 of the coated material.

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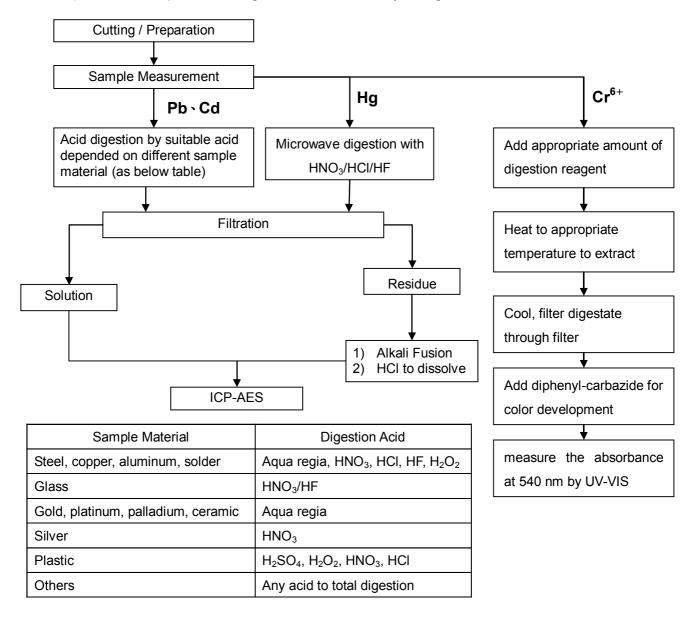


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- 1) These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) Name of the person who made measurement: Climbgreat Yang
- 3) Name of the person in charge of measurement: Troy Chang



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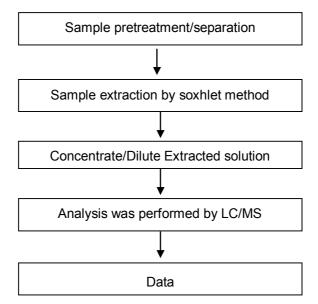
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Analytical flow chart of Soxhlet extraction (LC/MS) procedure

- 1) Name of the person who made measurement: Lydia Fu
- 2) Name of the person in charge of measurement: Shinjyh Chen
 - Test Items: PFOS/PFOA · Benzotriazole



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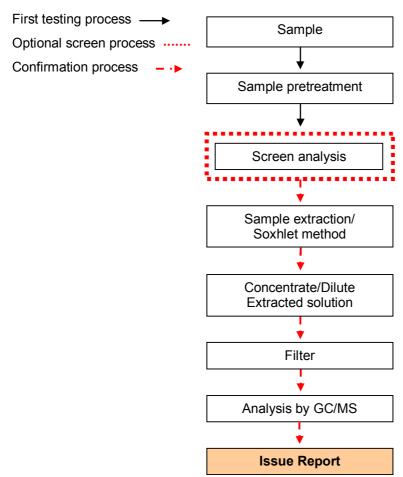
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YOKETAN CORPORATION 28-2, NAN 2ND ROAD, T. E. P. Z, TAICHUNG, TAIWAN



PBB/PBDE analytical FLOW CHART

- 1) Name of the person who made measurement: Roman Wong
- 2) Name of the person in charge of measurement: Shinjyh Chen



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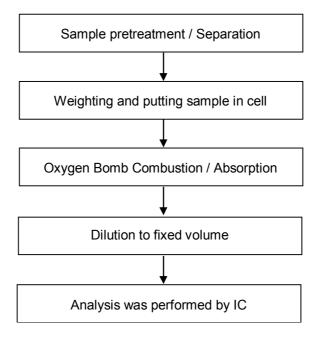
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YOKETAN CORPORATION 28-2, NAN 2ND ROAD, T. E. P. Z, TAICHUNG, TAIWAN



Analytical flow chart of halogen content

- 1) Name of the person who made measurement: Alan Chen
- 2) Name of the person in charge of measurement: Troy Chang



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** End of Report **

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